

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1210	Jul-97	9643 C1	ANAM, K.	DN634654AAA	3.0μ OX/NI	16 SOIC

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C):
HTC Vapor Phase
P-20045

Electrical
235/0 Cum %
0.0%

Sonoscan
P-20138

Post Vapor Phase
4/0

Infant / High Voltage Life
125°C, 7.0 V.
P-20139, P-20373

48 Hr 336 Hr 1KHr *Failure Rate
231/0 77/0

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-20374

300 ~ 1K ~ Cum %
39/0

Biased Moisture
85°C/85% RH, 5.5 V.
P-20375

274 Hr 959 Hr Cum %
77/0

Autoclave
121°C/100% RH, 2 Atmos
P-20376

96 Hr Cum %
38/0 0.0%

Failure Mode

Failure Analysis